

The Vienna Conference on Instrumentation

A new X-Ray imaging system based on Chromatic Photon Counting technology

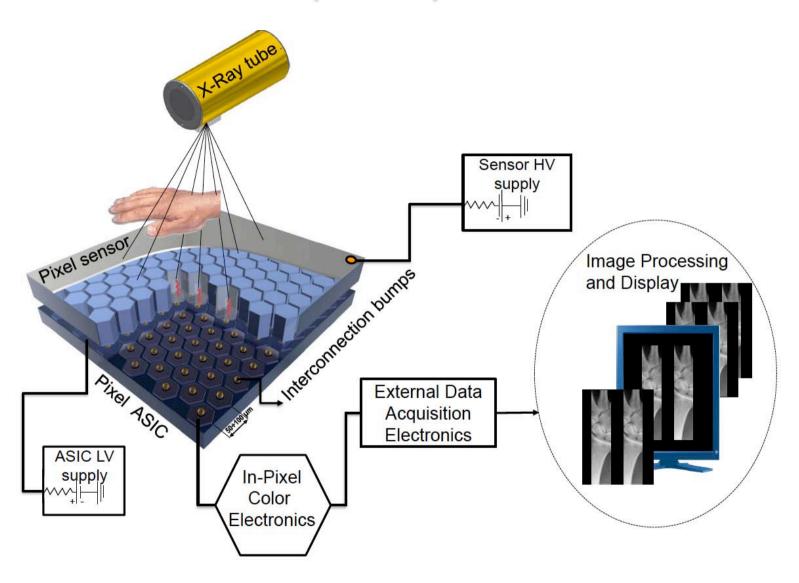
R. Bellazzini, G. Spandre, A. Brez, M. Minuti, M. Pinchera INFN Pisa & PIXIRAD Imaging Counters s.r.l.

P. Mozzo

PIXIRAD Imaging Counters s.r.l.



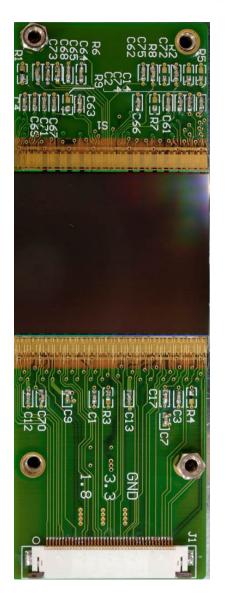
Principle of operation







The building block of the X-ray Imaging Sensor



Base block of PIXIRAD.

Hybrid architecture, obtained by coupling, with the *flip-chip bonding* technique:

- a CdTe X-ray sensor ($30 \times 25 \text{ mm}^2$, electron collection type)
- a pixellized CMOS ASIC (512×476 pixels, at 60 μm hex. pitch)

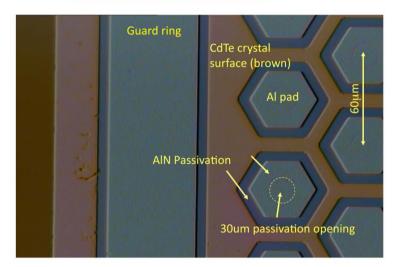
Main characteristics:

- color capability (2 counters / thresholds in each pixel)
- largest ASIC ever built on planet
- largest CdTe sensor with pitch finer than 100 µm ever built
- buttable on two sides
- very low global threshold
- automatic offset compensation





Passivation Metal CdTe





The CdTe Sensor

CdTe semiconductor characteristics:		
Atomic numbers	48, 52	
Effective atomic number	50	
Density ρ(g/cm³)	5.85	
Band energy (eV)	1.5	
Dielectric constant	11	
Ionizing energy (eV)	4.43	
Resistivity ρ(Ωcm)	10 ⁹	
Electron mobility μ _e (cm²/Vs)	1100	
Electrons mean lifetime $\tau_{_{e}}$ (s)	3x10 ⁻⁶	
Hole mobility μ _h (cm²/Vs)	100	
Holes mean lifetime τ_h (s)	2x10 ⁻⁶	
(μτ) _e (cm²/V)	3.3x10 ⁻³	
(μτ) _h (cm²/V)	2x10 ⁻⁴	

The CdTe pixel sensor (ACRORAD Co., Ltd.) is a Schottky type diode with electron collection on the pixels

Large area: $30.96 \times 24.98 \times 0.65$ mm

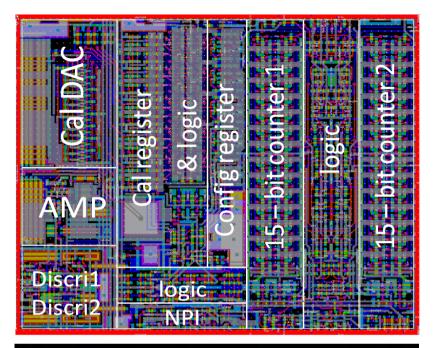
Pixel pitch: 60 μm (on hexagonal matrix)

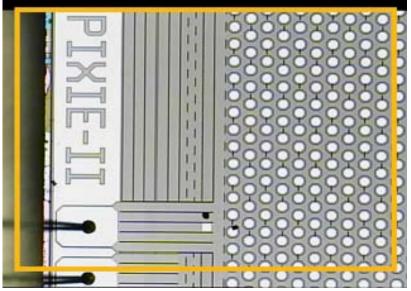
Very low leakage current @400-500V working voltage

 (5 nA/cm^2)









The CMOS large area ASIC

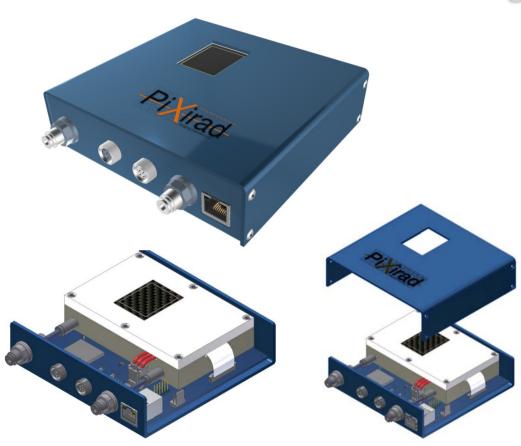
Pixel characteristics	
Shaped pulse duration (at the base)	1 μs (adjustable)
Linear range	> 3000 electrons
Saturation level	> 6000 electrons (>30 keV for CdTe)
Equivalent noise (ENC)	50 electrons (rms)
Residual offset after auto-calibration	± 30 electrons
Maximum number of counts before reading	32768
Input signal	positive or negative
Possibility to disable, swap, by pass, pixels	user selectable
Pixel reading	
Serialization of columns for best readout time	16, 32, 64, 128
Typical readout clock frequency	50 MHz
Readout time for 32 data outputs = 16 columns serialized (16 columns × 476 pixels × 15 bits × 20 ns)	2.3 ms
Readout time for 16 data outputs = 32 columns serialized	4.6 ms
Readout time for 8 data outputs = 64 columns serialized	9.2 ms

Data acquisition: 2 *color* reading (2 thresholds, 2 counters) or, alternatively, counting in one counter while reading the other one (dead-time free mode).





PIXIRAD-1 design concept



Inside the module:

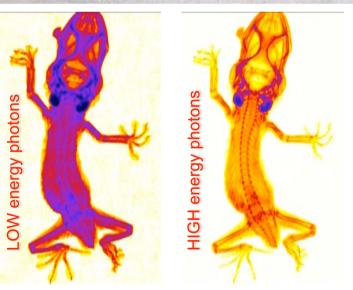
- 1 Gbit Ethernet DAQ
- Generation of High and Low Voltage Supply
- Distribution and cooling control

Externally: only 12V power supply (laptop type)



A single unit system (3×2.5 cm²)

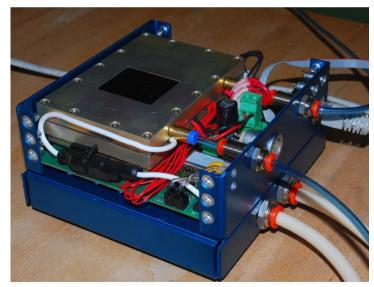






PIXIRAD-1: The module and the specs





Sensor specs:	CdTe, 650 µm, 30.9 × 25.0 mm ² Schottky type diode Electron collection at pixel
ASIC+CdTe base block	512 × 476 pixels
Number of blocks	1
Global active area	31 x 25 mm ²
Total number of pixels	243712
Total number of counters	487424
Pixel size	60 µm hexagonal arrangement
Pixel density	323 pixels/mm², equivalent to 55 µm on square arrangement
Pixel rate capability	10 ⁶ counts/pixel/s (after dead-time correction)
Global rate capability	2.4x10 ¹¹ counts/s
Pixel dead-time	300 ns
Position resolution	11 line pairs/mm at MTF 50%
Reading while taking data	possible
Energy range	1-100 keV
Detection efficiency @10 keV, 25 keV, 50 keV	100%, 100%, 98%
Counters depth	15 bits
Read-out time @50 MHz clock	5 ms/counter
Frame rate	200 readouts/s
Minimum applicable global threshold	200 electrons
Sensor bias voltage	200 ÷ 400 V
Leakage current density	5 nA /cm² at 400 V, -20 °C
Typical number of defective pixels	less than 1%
Number of independent thresholds (colors)	2 set of two (swappable in real time)
Camera specs:	
Size (W×L×H)	14×14×7 cm ³
Weight	< 2Kg
Power consumption	60 Watts (typical)
Cooling	liquid or forced air
Operating temperature	+40 -40 °C
197 - 19 Table 19 Tab	



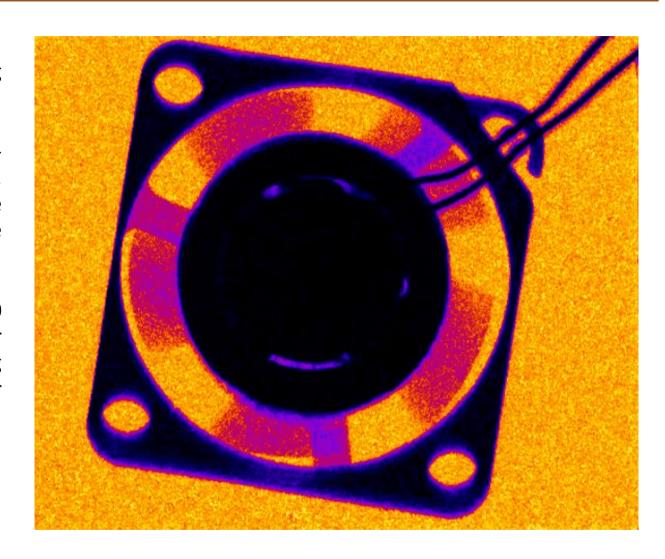


Dynamic Imaging

Image of a small fan spinning at around 4000 rpm.

The image was taken in Dead-Time Free mode (DTF), i.e. data are acquired in one counter while reading the other one.

The acquisition speed was 100 frame per second, shutter width was 1 ms and counting rate was 4×10^5 counts per pixel per second





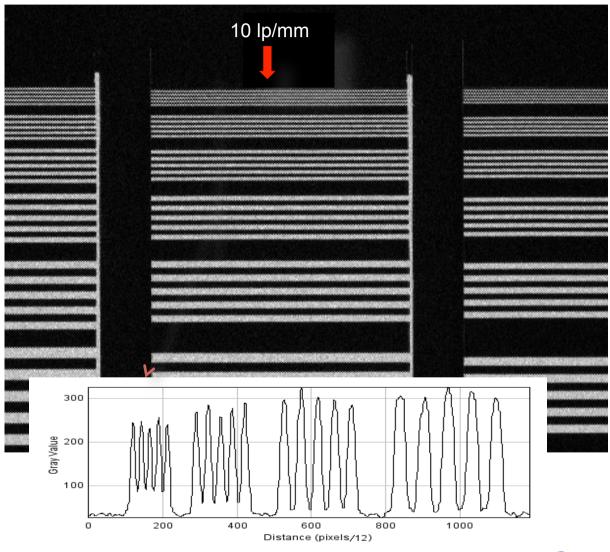


PIXIRAD-2

A 2 unit system $(6\times2.5 \text{ cm}^2)$

Image of a Hüttner mask to measure the resolving power









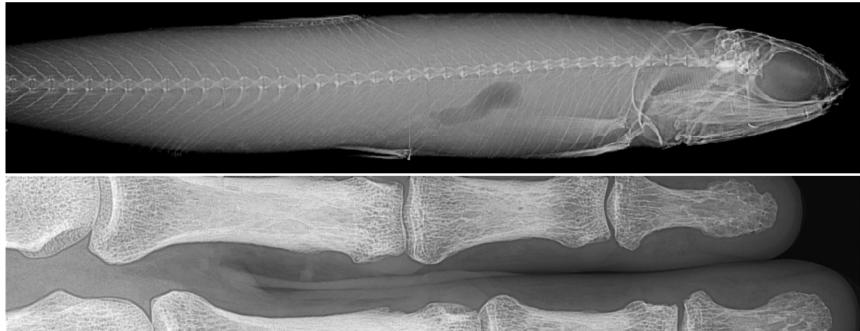


PIXIRAD-4

A 4 unit system

1M pixels, 2M counters,

12.1×2.5 cm² active area



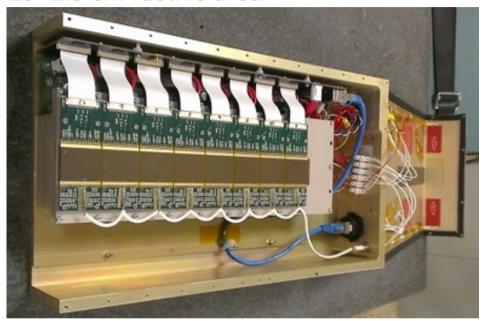


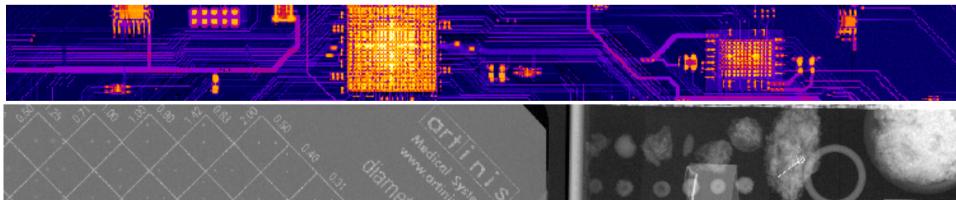


Pixel density Pixel rate capability Global rate capability Pixel dead-time Position resolution Reading while taking data square arrangement 105 counts/pixel/s 2x1011 counts/s 300 ns 11 line pairs/mm at MTF 50% possible		
electron collection at pixel ASIC+CdTe base block 512 × 476 pixels Number of blocks 8 Global active area 250 x 25 mm² Total number of pixels 1,949696 Total number of counters 3,899392 Pixel size 60 μm hexagonal arrangement Pixel density 323 pixels/mm², equivalent to 55 μm or square arrangement Pixel rate capability 2x10¹¹¹ counts/pixel/s Global rate capability 2x10¹¹¹ counts/s Pixel dead-time 300 ns Position resolution 11 line pairs/mm at MTF 50% Reading while taking data possible Dead-space between blocks 2 columns (to be reduced to 1 columns Energy range 1-100 keV Detection efficiency at 50 keV 98% Counters depth 15 bits Read-out time at 50 MHz clock 0.073 s Frame rate 13.6 fps Minimum applicable global threshold 200 electrons Cooling liquid or forced air Operating temperature +40 -40 C Sensor bias voltage 200 + 400 V Leakage current density 5 nA/cm² at 400 V,		
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Pixel density Pixel rate capability Global rate capability Pixel dead-time Position resolution Reading while taking data Dead-space between blocks Energy range Detection efficiency at 50 keV Counters depth Read-out time at 50 MHz clock Frame rate Minimum applicable global threshold Cooling Operating temperature Sensor bias voltage Leakage current density 2323 pixels/mm², equivalent to 55 μm of square arrangement 105 counts/pixel/s 2x10¹¹¹ counts/s 2x10¹¹¹ counts/s 2x10¹¹¹ counts/s 2x10¹¹¹ counts/s 2x10¹¹¹ counts/s 2columns (to be reduced to 1 columns 1-100 keV 98% 0.073 s Frame rate 13.6 fps Minimum applicable global threshold 200 electrons Cooling Uquid or forced air 440 -40 C Sensor bias voltage 200 ÷ 400 V Leakage current density 5 nA/cm² at 400 V, -30 C Typical number of defective pixels	Total number of counters	3,899392
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Detection efficiency at 50 keV 98% Counters depth 15 bits Read-out time at 50 MHz clock 0.073 s Frame rate 13.6 fps Minimum applicable global threshold 200 electrons Cooling liquid or forced air Operating temperature +40 -40 C Sensor bias voltage 200 ÷ 400 V Leakage current density 5 nA/cm² at 400 V, -30 C Typical number of defective pixels less than 10²	Dead-space between blocks	2 columns (to be reduced to 1 column)
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Read-out time at 50 MHz clock Frame rate 13.6 fps Minimum applicable global threshold Cooling Operating temperature Sensor bias voltage Leakage current density Typical number of defective pixels 0.073 s 13.6 fps 200 electrons liquid or forced air +40 -40 C 200 ÷ 400 V Leakage current density 5 nA/cm² at 400 V, -30 C	Detection efficiency at 50 keV	98%
Frame rate 13.6 fps Minimum applicable global threshold 200 electrons Cooling liquid or forced air Operating temperature +40 -40 C Sensor bias voltage 200 ÷ 400 V Leakage current density 5 nA/cm² at 400 V, -30 C Typical number of defective pixels less than 10-2	Counters depth	15 bits
Minimum applicable global threshold Cooling Operating temperature Sensor bias voltage Leakage current density Typical number of defective pixels 200 electrons liquid or forced air +40 -40 C 200 ÷ 400 V 5 nA /cm² at 400 V, -30 C less than 10-²	Read-out time at 50 MHz clock	0.073 s
Cooling liquid or forced air Operating temperature +40 -40 C Sensor bias voltage 200 ÷ 400 V Leakage current density 5 nA /cm² at 400 V, -30 C Typical number of defective pixels less than 10-2	Frame rate	13.6 fps
Operating temperature +40 -40 C Sensor bias voltage 200 ÷ 400 V Leakage current density 5 nA /cm² at 400 V, -30 C Typical number of defective pixels less than 10-2	Minimum applicable global threshold	200 electrons
Sensor bias voltage 200 ÷ 400 V Leakage current density 5 nA /cm² at 400 V, -30 C Typical number of defective pixels less than 10-2	Cooling	liquid or forced air
Leakage current density 5 nA /cm² at 400 V, -30 C Typical number of defective pixels less than 10-2	Operating temperature	+40 -40 C
Typical number of defective pixels less than 10 ⁻²	Sensor bias voltage	200 ÷ 400 V
	Leakage current density	5 nA /cm² at 400 V, -30 C
Number of independent thresholds (colors) 2 set of two (swappable in real time)	Typical number of defective pixels	less than 10 ⁻²
, , , , , , , , , , , , , , , , , , , ,	Number of independent thresholds (colors)	2 set of two (swappable in real time)

The giant PIXIRAD-8

A 8 unit system 2M pixels, 4M counters 25×2.5 cm² active area



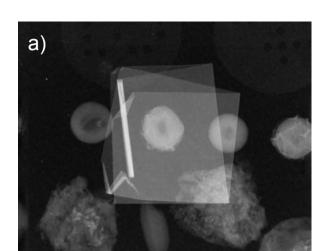


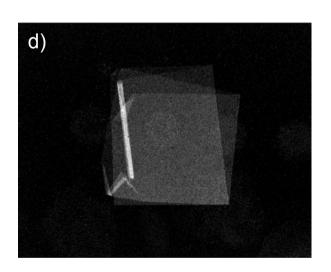




Chromatic photon counting

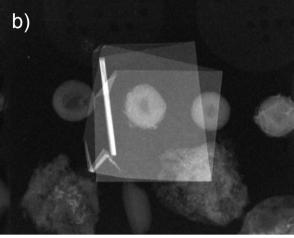
All energies photons image



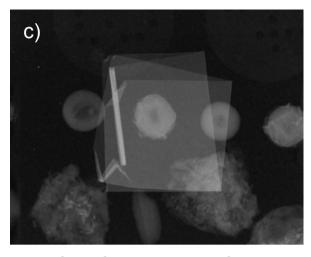


High energy photons image.

High thresh just > Zr K edge



Low energy photons image: a) – b) (En < Zr K edge)



Ackermann phantom superimposed with a 2 μm Zr sheet. The Zr foil has been irregularly folded to simulate different thicknesses (2-8 μm). Kedge Zr: 17.9 KeV

Image d) =b) - 0.7 c)

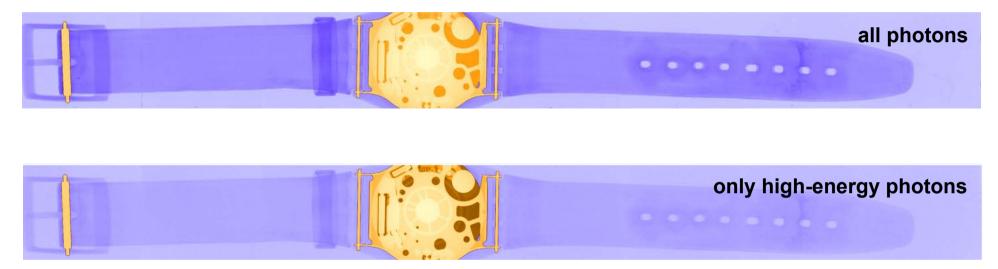
The Ackermann phantom structures disappear, leaving visible the Zirconium sheet. The factor 0.7 is chosen to roughly equalize the counts in the Low and High energy image.





Chromatic photon counting

Single shot X-ray image of a man watch with its leather band

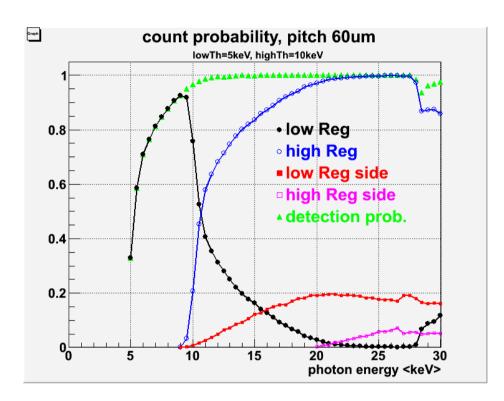


The watch is made of plastic and metal parts. The top image better visualizes low absorbing materials (plastic, leather), the bottom image better visualize the metal parts



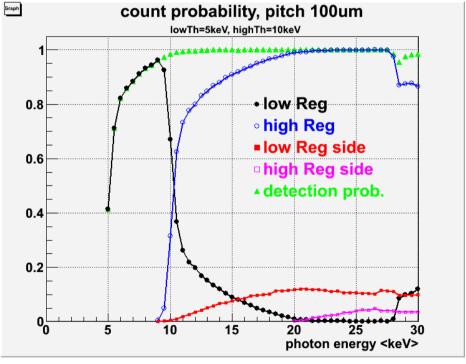


Two thresholds detector count probability



low Register: 5keV < Energy < 10 keV

high Register: Energy > 10 keV







Sensitivity to low energy photons

Images of a very low contrast objects





200 electrons global threshold corresponding to 1 keV (all photon, LOW counters)

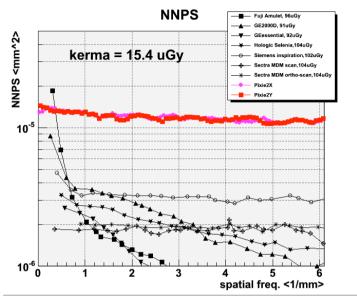


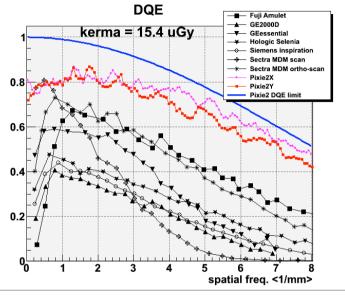
1200 electrons global threshold corresponding to 6 keV (high energy photons, HIGH counter)

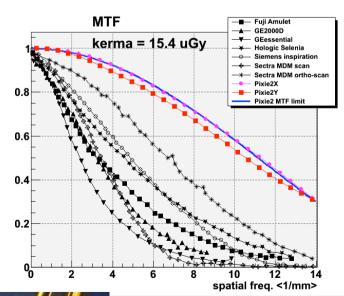


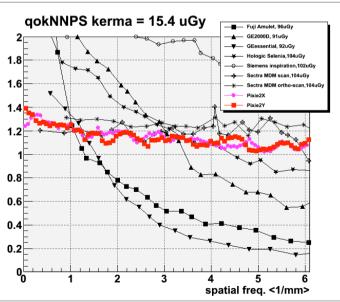


PIXIRAD characteristics for digital mammography







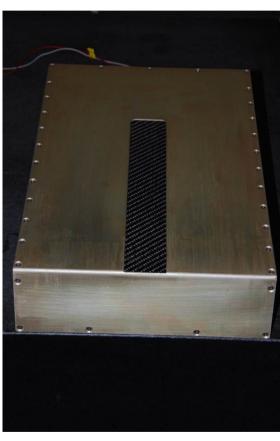






PIXIRAD-8 application to digital mammography





Complete module includes;

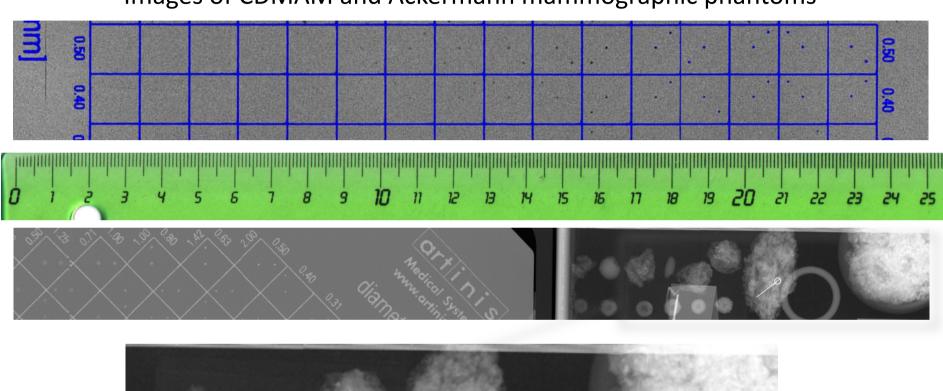
- 8 unit sensor
- -25×2.5 cm² active are
- 2 M pixel 4M counters
- 2 pixel inter-modules spacing
- almost edge less toward the breast
- DAQ electronics
- Cooling system
- 1 Gbit Ethernet connection

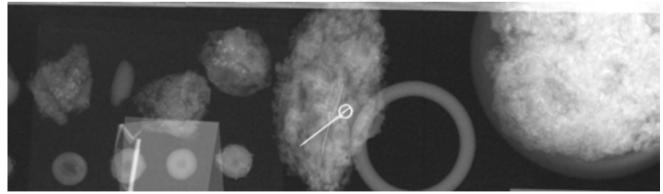




PIXIRAD-8 application to digital mammography

Images of CDMAM and Ackermann mammographic phantoms









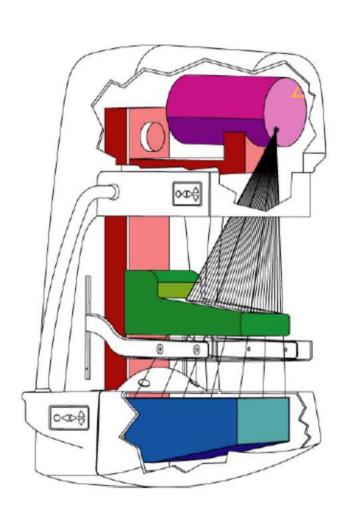
PIXIRAD-8 assembling phases

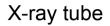






The X-ray slot-scanning imaging system





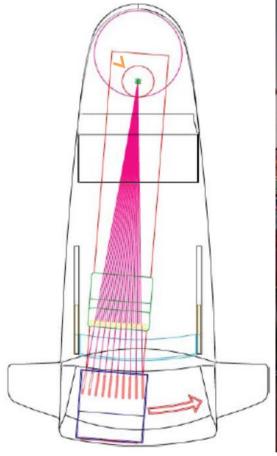


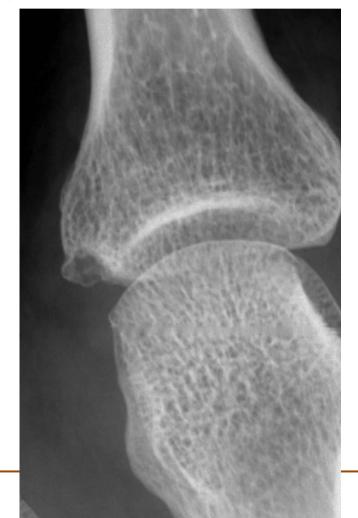


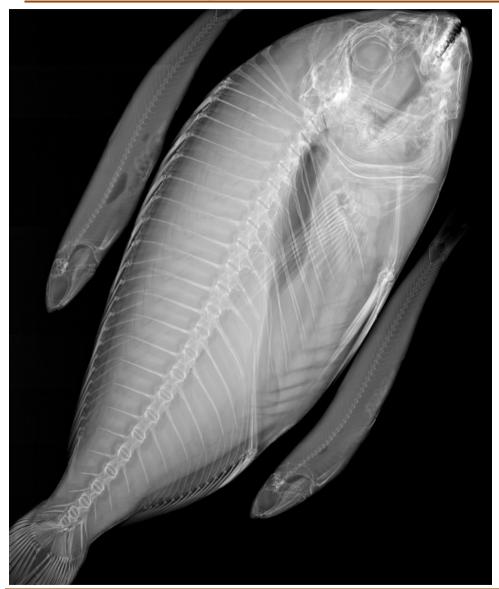






Image of a human hand (no image treatment) taken in slot-scanning mode at 35 kVp tube voltage and with a silver filter and a detail of a finger junction.



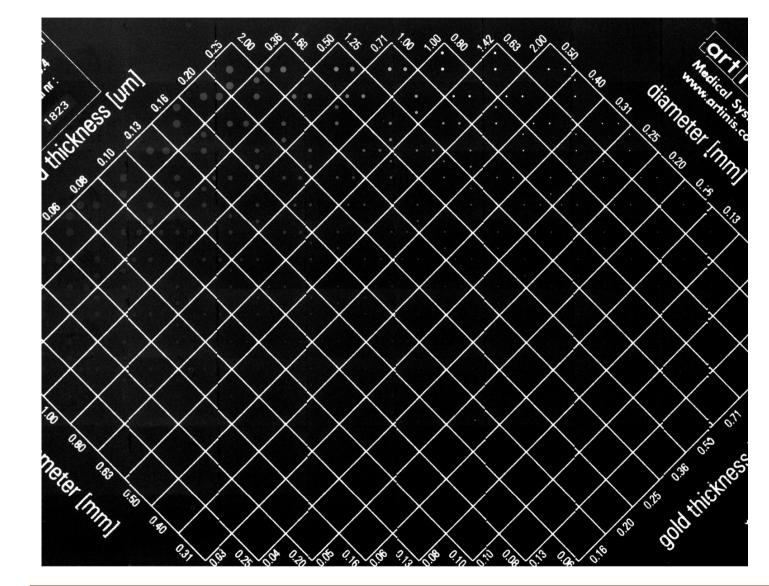




A large area (25x20 cm²) image of a sea-bass fish and two anchovies taken in slot-scanning mode and a detail of mouth and teeth







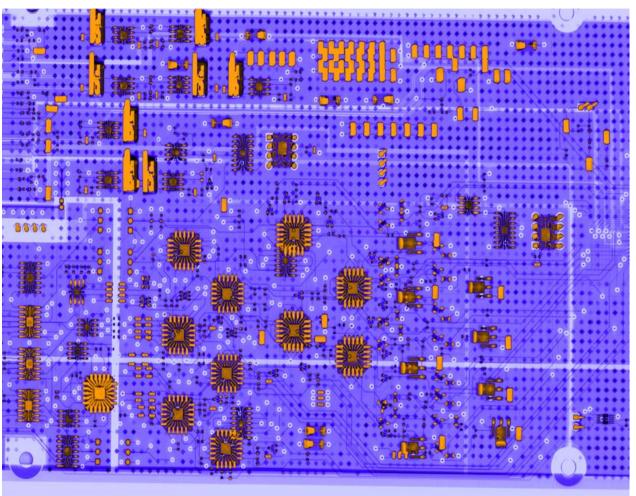
A CDMAM contrastdetail phantom image.

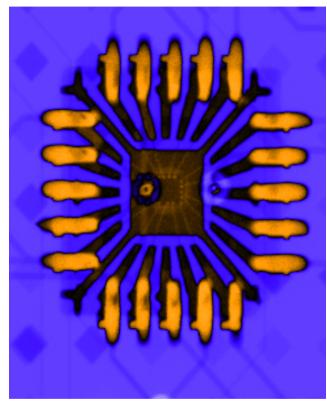
The image has been taken in a configuration equivalent to a 32 mm thick breast (27kvp, 50mas, no filtration).

We can detect the 0.5 mm diameter detail down to 0.05 μ m thickness, the 0.25 mm down to 0.08, the 0.1 mm down to 0.36







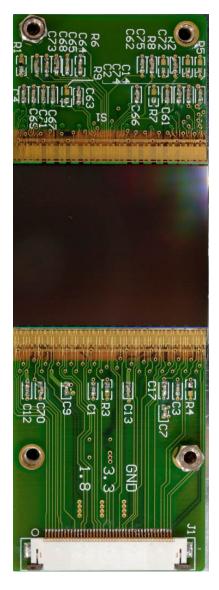


Large PCB imaged in slot-scanning mode. In the detail on the right the wire bondings inside an electronic package are neatly visible





Conclusions



An innovative X-ray Imaging Sensor based on Chromatic Photon Counting technology has been presented.

The detector can deliver extremely clear and highly detailed X-ray images for medical, biological, industrial and scientific applications in the energy range 1-100 keV.

Photon counting, *color* mode and very high spatial resolution (11 lp/mm at MTF50) allow to obtain an optimal image quality/absorbed dose ratio.

1, 2, 4, 8 tiles modules units with almost zero dead space between the blocks have been built.

A complete X-Ray camera based on PIXIRAD-1 single module assembly is available for customers in scientific and industrial markets .

A dedicated machine to perform X-ray slot-scanning imaging has been designed, built and is currently under test. The system utilizes the PIXIRAD-8 module and is able to produce very large area images, with fine position resolution. This system has been designed for Digital Mammography, one of the most demanding X-ray imaging applications.

The X-ray Imaging System is the technological platform of PIXIRAD Imaging Counters s.r.l., a recently constituted INFN spin-off company.

PIXIRAD web site: http://pixirad.pi.infn.it



